

### AMENDMENTS TO THE SPECIFICATION

Please amend the specification as follows. Please replace paragraph [0019] of the specification as originally filed with the paragraph below, which is marked-up to show the changes therein:

[0019] In accordance with a feature of an embodiment of the present invention, a method for classifying defects of an object includes irradiating lights having different polarizations ~~wavelengths~~ onto the object to create an inspection spot on the object, collecting scattered lights generated by the irradiated lights scattering from the inspection spot, and classifying defects of the object by type of defect by analyzing the scattered lights. In the method, irradiating lights having different polarizations ~~wavelengths~~ may include irradiating a first light and a second light onto the inspection spot, wherein a first scattered light and a second scattered light are generated by the first light and the second light, respectively, scattering from the inspection spot. Irradiating the first light and the second light may further include generating a first polarized light and a second polarized light from the first light and the second light, respectively, using a polarizer, wherein the first polarized light and the second polarized light are irradiated onto the inspection spot. The first polarized light and the second polarized light may be two different lights selected from the group consisting of a primary polarized (P) light, a secondary polarized (S) light and a circular polarized (C) light. The first light may be positioned opposite to the second light.

Also, please replace paragraph [0026] of the specification as originally filed with the paragraph below, which is marked-up to show the changes therein:

[0026] The lights having different polarizations ~~wavelengths~~ may be generated from a single light source. The lights may be irradiated onto an incident face of the object at an angle of about 10° to about 30°. The scattered lights may be collected at an angle in a range of about 40° to about 50° relative to irradiation directions of the lights with reference to the inspection spot.

Also, please replace paragraph [0029] of the specification as originally filed with the paragraph below, which is marked-up to show the changes therein:

[0029] In accordance with another feature of an embodiment of the present invention, an apparatus for classifying defects of an object includes light creating means emitting lights having different polarizations ~~wavelengths~~ to create an inspection spot on the object and a detecting member for collecting scattered lights that are created from the lights scattering from the inspection spot, wherein the scattered lights are analyzed and classified in accordance with defects positioned on the inspection spot of the object.